ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

SEMICONDUCTOR DEVICE

Application Number:

Confirmation Number:

First Named Applicant:

Kaoru INOUE

Attorney Docket Number:

28569.7636

Art Unit:

2814

Examiner:

Long Pham

Search string:

(6639255 or 6483135 or 6274889 or 6184547 or 5374835 or 6316793 or 6064082

or 5399886 or 20020066908).pn

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
Fe	1	6639255	2003-10-28	Inoue, et al.			• • • • • • • • • • • • • • • • • • • •
PE	2	6483135	2002-11-19	Mizuta, et al.			
P8	3	6274889	2001-08-14	Ota, et al.			
PX	4	6184547	2001-02-06	Onda			
PB	5	5374835	1994-12-20	Shimada, et al.			
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PC	7	6064082	2000-05-16	Kawai, et al.			· <u>-</u>
PS	8	5399886	1995-03-21	Hasegawa			

US Published Applications

Note: Applicant is not required to submit a paper copy of cited US Published Applications

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
R	1	20020066908	2002-06-06	Smith			

Signature

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